520.43429X00

November 7, 2005

T AND TRADEMARK OFFICE

Applicants: YOSHIDA et al

Serial No.: 10/765,920

Filed: January 29, 2004

Pattern Defect Inspection Method And Its Apparatus

Group: 2878

M. Zettl Examiner:

## INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97 & 1.98

Mail Stop: DD

**Commissioner For Patents** 

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

For:

In the matter of the above-identified application, applicants are submitting herewith copies of the non-US patent documents as listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted before the mailing date of either a final action or a notice of allowance and is accompanied by the fee of \$180.00 set forth in 37 CFR 1.17(p).

To the extent the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language version Abstract, an English language patent family member and the discussion of these documents in the specification.

It is respectfully requested that this information disclosure statement and the

listed documents be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus, LLP, Deposit Account No. 01-2135 (Case: 520.43429X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

Paul J. Śkwierawski

Registration No. 32,173

MK/PJS/jla (703) 312-6600 Attachments

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# **U.S. PATENT DOCUMENTS**

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#### **U.S. PATENT APPLICATIONS**

	Publication Number	Name	Publication Date
Al	2001-0025924 A1	Uto et al	10/01
AJ			
AK			
AL			

### FOREIGN PATENT DOCUMENTS

	Doc. No.	Date	Country	Class	Subclass	Translation/Abstract?	
						Yes	No
AM	8-320294	12/96	Japan			Abstract	
AN	10-78668	3/98	Japan			Abstract	-
AO	2001-176942	6/01	Japan			Abstract	
AP	2001-194323	7/01	Japan			Corresponds to Document AA	
AQ	2001-296570	10/01	Japan			Corresponds to Document AI	

#### **OTHER DOCUMENTS**

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